Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/849,570	ABELARD ET AL	
Examiner	Art Unit	
Thai Tran	2616	

SEARCHED			
Class	Subclass	Date	Examiner
386	6-8, 33, 68-70, 81- 82, 111- 112	5/28/2005	πα
375	240.05	5/27/2005	тто
375	240.07	5/27/2005	πα
375	240.12	5/27/2005	тτα
H04N	5/76	5/27/2005	TTQ
H04N	5/781	5/27/2005	TTQ
H04N	7/12	5/27/2005	πо
nodate	of the	above, s	eart
7		10/28/05	110
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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